

Joint ICTP-IAEA School on Novel Experimental Methodologies for  
Synchrotron Radiation Applications in Nano-science and Environmental  
Monitoring | (smr 2611)

Contribution ID : 56

Type : not specified

## Quantitative XRF analysis: algorithms and their practical use

*Thursday, 20 November 2014 16:00 (1:00)*

**Content**

**Summary**

**Presenter(s) :** P. VAN ESPEN (University of Antwerpen - Belgium)

**Session Classification :** not yet classified